

Notice of References Cited	Application/Control No.	Applicant(s)/Patent Under Reexamination
	09/913,014	FAN ET AL.
	Examiner Lynne Edmondson	Art Unit 1725

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-6,323,943	11-2001	Maruyama et al.	356/28.5
*	C	US-5,734,108	03-1998	Walker et al.	73/650
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*	E	US-4,854,494	08-1989	von Raben, Klaus-Ulrich	228/1.1
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
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	W	
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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